

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((recogni\$4 or identif\$7 or determi\$5 or read\$3) near5 (stroke or handwritt\$3 or user\$1drawn or hand\$1drawn)) and (stylus or pen or handheld) and (signal near7 sampl\$3 near7 (predetermin\$3 or predefi\$3 or set or limit\$3)) and (bandpass near5 filter) and ((vector) same position same (interval or increment)) and classif\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/08/09 15:39
L2	0	(signal same (analy\$4) same (stylus or pen or handheld)) and (signal near7 sampl\$3 near7 (predetermin\$3 or predefi\$3 or set or limit\$3)) and (bandpass near5 filter) and ((vector) same position same (interval or increment)) and classif\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/08/09 15:40
L3	5	(signal same (analy\$4) same (stylus or pen or handheld)) and (signal near7 sampl\$3 near7 (predetermin\$3 or predefi\$3 or set or limit\$3)) and (bandpass near5 filter)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/08/09 15:43
L4	0	(signal same (analy\$4) same (stylus or pen or handheld)) and (signal near7 sampl\$3 near7 (predetermin\$3 or predefi\$3 or set or limit\$3)) and ((vector or gradient) same position same (interval or increment)) and classif\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/08/09 15:43

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(handhel...
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